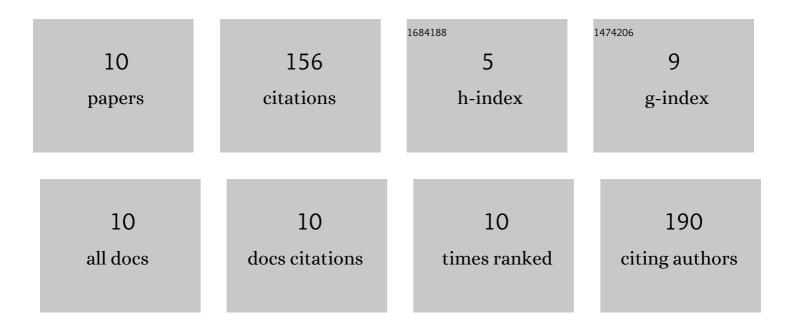


## List of Publications by Year in descending order

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DENCL

#	Article	IF	CITATIONS
1	Recent development of PeakForce Tapping mode atomic force microscopy and its applications on nanoscience. Nanotechnology Reviews, 2018, 7, 605-621.	5.8	78
2	Phase modulation mode of scanning ion conductance microscopy. Applied Physics Letters, 2014, 105, .	3.3	22
3	In-Phase Bias Modulation Mode of Scanning Ion Conductance Microscopy With Capacitance Compensation. IEEE Transactions on Industrial Electronics, 2015, 62, 6508-6518.	7.9	17
4	Development of Mechanostimulated Patch-Clamp System for Cellular Physiological Study. IEEE/ASME Transactions on Mechatronics, 2014, 19, 1138-1147.	5.8	15
5	Amplitude Modulation Mode of Scanning Ion Conductance Microscopy. Journal of the Association for Laboratory Automation, 2015, 20, 457-462.	2.8	11
6	Nanopatterning on calixarene thin films via low-energy field-emission scanning probe lithography. Nanotechnology, 2018, 29, 325301.	2.6	4
7	Advances in Scanning Ion Conductance Microscopy: Principles and Applications. IEEE Nanotechnology Magazine, 2021, 15, 17-25.	1.3	3
8	Development of a multi-functional multi-probe atomic force microscope system with optical beam deflection method. Review of Scientific Instruments, 2021, 92, 123705.	1.3	3
9	Lateral force calibration for atomic force microscope cantilevers using a suspended nanowire. Nanotechnology, 2020, 31, 475703.	2.6	2
10	High-speed Atomic Force Microscope Technology: A Review. Current Nanoscience, 2022, 18, 545-553.	1.2	1